

Docket No. 240262US2S/hc



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Kenichi IMAMIYA, et al.

SERIAL NO: 10/617,400

GAU: 2818

FILED: July 11, 2003

EXAMINER:

FOR: NONVOLATILE SEMICONDUCTOR MEMORY AND ITS TEST METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

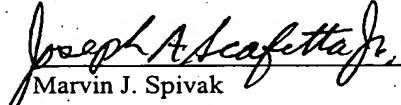
No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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DOCKET NO.: 240262US2S/hc

Page 1 of 1

MAILED MAR 23 2004
U.S. PATENT & TRADEMARK OFFICE
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MAIL DATE CANCELLED

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STATEMENT OF RELEVANCY

All of the references on Form PTO 1449 are discussed in the specification.

MAR 23 2004

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SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
240262US2SSERIAL NO.
10/617,400

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Kenichi IMAMIYA, et al.FILING DATE
July 11, 2003GROUP
2818

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						
AM						
AN						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
AO	2001-176290	06/29/2001	JAPAN		X
AP					
AQ					
AR					
AS					
AT					
AU					
AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AW	K. IMAMIYA, et al., IEEE Journal of Solid-State Circuits, vol. 34, no. 11, pages 1536-1543, "A 130-mm ² , 256-Mbit NAND FLASH WITH SHALLOW TRENCH ISOLATION TECHNOLOGY", November 1999
AX	K.-D. SUH, et al., ISSCC95 / SESSION 7 / FLASH MEMORY / PAPER TA 7.5, Digest of Technical Papers, pages 128-129, "A 3.3V 32Mb NAND FLASH MEMORY WITH INCREMENTAL STEP PULSE PROGRAMMING SCHEME", February 16, 1995
AY	
AZ	

 Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.